



XA-9999
PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the application of:

Tomohiro MIYASHITA

Appln. No.: 10/721,994

Filed: November 26, 2003

For: MICROSCOPE OPTICAL SYSTEM AND MICROSCOPE OBJECTIVE
LENS

* * *

SUPPLEMENTAL
INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Supplementing the Information Disclosure Statement
dated November 26, 2003, and without any assertion as to
materiality or prior art effect, the documents listed on
the attached Form PTO-1449 are hereby cited.

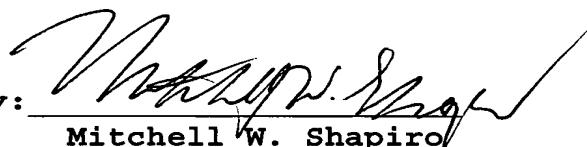
English abstracts of the listed documents were
submitted with the Information Disclosure Statement dated
November 26, 2003. Enclosed herewith are copies the
Japanese Laid-Open Patent Applications cited.

The Commissioner is hereby authorized to charge to Deposit Account No. 50-1165 any fees under 37 C.F.R. §§ 1.16 and 1.17 that may be required by this paper and to credit any overpayment to that Account. If any extension of time is required in connection with the filing of this paper and has not been requested separately, such extension is hereby requested.

Respectfully submitted,

MWS:ah

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By: 
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February 17, 2004

FORM PTO-1449			Atty. Docket No. XA-9999	Appln. No. 10/721,994		
<u>LIST OF DOCUMENTS CITED BY APPLICANT</u>						
			Applicant Tomohiro MIYASHITA			
			November 26, 2003		Group	
U.S. PATENT DOCUMENTS						
Examiner Initial	Document Number	Date	Name	Class	Sub-class	
AA						
AB						
AC						
AD						
AE						
AF						
AG						
AH						
AI						
FOREIGN PATENT DOCUMENTS						
Examiner Initial	Document Number	Date	Country	Class	Sub-class	Translation
AJ	✓ 2000-171721	06/23/00	Japan			Abstract
AK	✓ 2001-166215	06/22/01	Japan			Abstract
AL	✓ 09-033818	02/07/97	Japan			Abstract
AM						
AN						
AO						
OTHER (including author, title, date, pertinent pages, etc.)						
AP						
AQ						
AR						
Examiner			Date Considered			
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.						